

# SOIL

## X-MET® for soil analysis

Fast, on-site soil screening

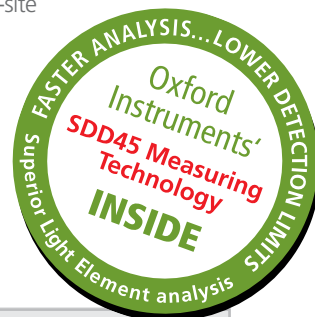
Most cost effective testing

### Accurate heavy element analysis down to ppm levels!



At the pull of a trigger, the **X-MET5000** and **X-MET5100** X-ray fluorescence (XRF) analysers provide fast, highly accurate, on-the-spot sample screening and analysis. The need for expensive laboratory testing is minimal. **X-MET** enables GPS integration for real-time correlation of measurement data and location coordinates.

- Accurate and reliable identification of heavy element pollutants
- Define the extremities of 'hotspots' in seconds
- Easy data transfer to PC assures maximum efficiency and minimum errors when working on-site
- Pre-sort contaminated soil to minimize remediation costs
- Soil remediation decisions made instantly
- Fast and reliable Go/No-Go decisions, and fully configurable Pass/Fail alarms



#### High speed on-site measurement:

- Rapid, simple on-site screening
  - Directly from the ground
  - In sample bags or cups
- Laboratory quality analytical data by measuring prepared samples in bench-top mode
- Analyze any sample type, including soil, rock, dirt, humus, sand, powder, liquid etc.

Silicon Drift Detector technology improves productivity!

Top of the range **X-MET5100** combines Oxford Instruments' groundbreaking Silicon Drift Detector (SDD) with a powerful 45kV X-ray tube. This cutting edge technology delivers a five times faster measurement speed, much better detection limits and significant accuracy improvement over conventional systems. Isn't it time you used **X-MET** to improve your productivity and screening confidence?



## Rugged and reliable tool for fast analysis

- Withstands all weather conditions and rough treatment
- IP54 (NEMA 3) approved. Superior dust and moisture protection
- High-strength environmentally sealed housing
- Long battery operating time, charge indicator on battery and user interface



Splash and dust proof cover

## High performance

- Fast, single-shot heavy element analysis: Pb, As, Cr, Cu, Zn, Ni, Cd, Co, Se, Mo, Hg, Sb, Ag, Ba etc.
- Al, Si, P, S analysis of prepared samples. No need for vacuum or He attachments! (**X-MET5100**)
- Fast measurement time: 30 – 120 seconds (**X-MET5000**) or 5 – 30 seconds (**X-MET5100**), depending on the elements of interest and required precision
- Low detection limits, **X-MET5000** can typically detect 5 – 30 ppm concentration with a 120s measurement time. **X-MET5100** detection limits are even lower and ppm level analysis can be achieved in just 10 – 30 seconds
- Measures all 26 elements defined in EPA6200
- High speed automatic averaging: Calculates averages of 2 – 50 measurements and saves individual results and averaged results



## Easy and reliable

- Short learning curve
- User interface in >10 languages
- Easy data storage and reporting
- PDA based technology for flexibility
- CE, cCSAus certified

## Bench-Top Stand and portable sample bag adapter

- Improved precision
- Lower detection limits
- Optimized accuracy
- Operator-selectable, comfortable location



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